



Form PTO-1449

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PATENT INFORMATION DISCLOSURE CITATION

Attorney's Docket No. WOLFF-4	Applicant Thomas Wolff	Appl. No. 10/693,771
Filing Date October 24, 2003	Group	Examiner

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date, if appropriate

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EC		Adesida et al.: "Dry and Wet Etching for Group III-Nitrides", 1999
↓		Youtsey et al.: "Smooth n-type GaN surfaces by photoenhanced wet etching", 1998
↓		Notten et al.: "Etching of III-V Semiconductors", 1991

Examiner: <i>Archer</i>	Date considered: 7/12/05
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*Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

Attorney's Docket No. WOLFF-4	Applicant THOMAS WOLFF	Appl. No. 10/693,771
Filing Date October 24, 2003	Group 1765	Examiner Chen, Eric Brice

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date, if appropriate

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation
EC ↓	DE 195 10 852 A1	09-21-1995	Germany			no
	DE 41 26 916 A1	02-18-1993	Germany			no

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner: <i>Eric Chen</i>	Date considered: <i>7/12/05</i>
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